

ABSTRACT

The present invention concerns an apparatus and method for absorbance detection in instrumental situations which have short absorption path lengths, such as microchip type devices. By modulating the sample beam incident upon a sample cell, the sensitivity of the absorbance measurement is improved. The modulation means includes a scanning device arranged to move the sample beam from a first position in which the sample beam is incident upon said sample area to a second position in which the sample beam is incident upon the cell.

Figure 1.